

Search Notes

Application/Control No.

10/611,393

Examiner

shih-wen hsieh

Applicant(s)/Patent under
Reexamination

LO ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22,29,30 31,36	2/6/2007	SWH
442	392	2/6/2007	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR